Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/755,635	ZADEREJ ET AL.
Examiner	Art Unit
Hae M. Hyeon	2839

SEARCHED					
Class	Subclass	Date	Examiner		
-					
		<u> </u>	<u> </u>		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
439	74	4/05	honh	
439	931	V	1	
	•			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Update Search Done	4/05	hmh		
·				